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- (71) Applicant (for all designated States except US): INTER-NATIONAL BUSINESS MACHINES CORPORA-TION [US/US]; New Orchard Road, Armonk, NJ 10504 (US).
- (72) Inventors; and
- (75) Inventors/Applicants (for US only): RAINEY, Beth, Ann [US/US]; 702 Oak Knoll Road, Williston, VT 05495 (US). NOWAK, Edward, J. [US/US]; 8 Windridge Road, Essex Junction, VT 05452 (US). ALLER, Ingo, Dr. [DE/DE]; Hegelstrasse 12, 71093 Weil im Schoenbuch (DE). KEIN-ERT, Joachim [DE/DE]; Hoelderlinstr. 27, 71155 Altdorf (DE). LUDWIG, Thomas [DE/DE]; Im Winkel 10, 71063 Sindelfingen (DE).
- (74) Agent: PEPPER, Margaret, A.; International Business Machines Corporation, Dept. 18G, Building 300/482, 2070 Route 52, Hopewell Junction, NY 12533 (US).

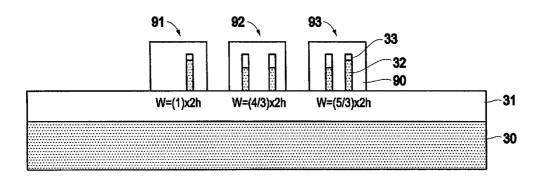
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(54) Title: MULTI-HEIGHT FINFETS



(57) Abstract: The present invention provides a FinFET device that has a first fin and a second fin. Each fin has a channel region and source and drain regions that extend from the channel region. The fins have different heights. The invention has a gate conductor positioned adjacent the fins. The gate conductor runs perpendicular to the fins and crosses the channel region of each of the first fin and second fin. The fins are parallel to one another. The ratio of the height of the first fin to the height of the second fin comprises a ratio of one to 2/3. The ratio is used to tune the performance of the transistor and determines the total channel width of the transistor.

# INTERNATIONAL SEARCH REPORT

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Electronic da INSPEC; IEF	ata base consulted during the international search (nam BE	ne of data b	ase and, where practicable, sear	ch terms used)	
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International application No. PCT/US04/02647

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